

XFEL diagnostics, detectors, optics

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Introduction: XFEL jitter



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C. Milne et al., Appl. Sci. 7, 720 (2017).

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A real XFEL pulse:











X-ray Free Electron Lasers - XFELs



In a model case: A real XFEL pulse: Pulse number: 1 Intensity Intensity Energy Energy Time Time

Introduction: XFEL jitter

total numer of photons per pulse – area under curve, with monochromator













Introduction: Requirements for pulse diagnostics – Machine



Operators and machine experts:

- Want to know machine performance for commissioning, improvement, and monitoring.
- On-line/non-invasive:
 - Pulse energy
 - Spectral distribution
 - Position (Poynting vector)
 - Pulse length
- Invasive
 - Tools for optimization of insertion devices.
 - Devices to measure gain curves of pre-SASE beams.
 - Profile monitors

Introduction: Requirements for pulse diagnostics – Users



Experimental users:

- Want to know the pulse-to-pulse beam parameters for data analysis and signal monitoring.
- On-line/non-invasive:
 - Pulse energy
 - Spectral distribution
 - Position (Poynting vector)
 - Pulse length
 - Arrival time
- Invasive
 - Photon pulse transverse profile.





Microchannel plate (MCP) detectors – used in the undulator section.

Undulators should be pointing in the same right direction. To align them, one needs to use a series of MCP detectors to get images of the photon beam as it goes through the subsequent undulators. Although an extremely weak signal needs to be visualized, it does not need to be a shot-to-shot measurement. Without this alignment procedure, the SASE (self-amplified spontaneous emission) is inefficient, and the light may shine all over the place, each undulator emitting the photons in a different direction, causing the light to become diffuse and more jittery.









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gap (mm) A gain/gap curve is measured to see if the gaps correspond to the correct photon energies. To do this, one sets the monochromator at a certain energy, and scans the gap opening of the undulators, looking at the gain from diodes or MCP detectors for the best performance.







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XFEL beam positioning and profiling: MCP detector, diode MCP readings





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- Since the pulse energy changes shot-to-shot, you need to measure the intensity of the FEL beam on a shot-to-shot basis.
- If the beam is monochromatic, the intensity fluctuations can be as much as 100%, i.e. you get no light in some pulses since there is a mismatch between the spectrum of the FEL and the settings of a monchromator. Being able to filter out the bad shots by noting that there was no energy in them becomes invaluable. If you do not have this ability, you do not know if the lack of signal you saw is real (i. e. related to the dynamics in the sample of interest), or you simply did not get the light necessary for the signal.
- Most importantly, pulse energy measurement must be non-invasive, to allow users to conduct their experiment at the same time. In other words, the pulse energy must be measured in such a way to allow the light to reach the experiment with minimum interference.



- Gas ionization chambers measure pulse energy by counting the number of ions generated in a gas medium.
- Direct current measurements are used for absolute numbers, but are slow.
- Multiplier signal measurements are good for fast measurements, but are relative.
- Fast and slow measurements are combined to get an absolute pulse energy for every pulse.





- Thin diamond or Si₃N₄ foils let most of the beam through, and the elastically backscattered photons are detected by the four diodes. Backscattering monitor is used to measure the relative pulse intensity and the position of the beam.
- Here, too, the reference data for the coherent and incoherent scattering of light from the materials are found in old experimental texts, though people have made programs for the evaluation these days.
- Very compact, useful for end-station measurement of pulse energies.





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Pulse profile measurement: scintillating screen, optics, camera



Even something as simple as a 2-dimensional visible light-camera (e. g. CCD) can be adapted for better accuracy. In the design shown the mirror and the camera do not move — only the scintillating screen does (because of the XFEL beam damage). The camera always looks at the exact same spot, so any motion detected can only come from the motion of the beam.

Pulse profile measurement: scintillating screen, optics, camera



Online measurement of the XFEL beam spectra is all about Bragg diffraction. One equation to remember – the Bragg's diffraction law:

$$2d * \sin\theta_B = n\lambda = n\frac{hc}{E}$$

, where d – lattice spacing constant, θ_B – Bragg angle, n – diffraction order (n=1,2,3,...), λ – wavelength, h – Planck's constant, c – speed of light, E – photon energy.



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Pulse spectrum measurement: grating,

X-ray spectrometers







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Use a grating to split off a part of the beam to shoot onto a bent crystal spectrometer. This allows us to see whole spectrum while letting main beam (>95%) through.

• XFEL pulse arrival time



XFEL pulse arrival time

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Pulse number: 1 2000 Number of pulses 18499 pulses 1750 FWHM=60.8 fs Intensity 1500 1250 1000 750 500 250 0 -50 50 100 -150-100Ó 150 Time Arrival time (fs)

• XFEL pulse duration (or length)

•

M. Harmand et al., Nature Photonics 7, 215 (2013).

Can only measure arrival time, not pulse duration.

Has a large window to work over.

- be invasive Can at low photon energies.
- Reliable tool requiring less setup than the THz streaking.
- Could be hard to find the signal since the edge may be weak.

100

550

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Summary

- Photon Diagnostics are necessary for the proper function and use of current X-ray FELs.
- It is an interesting mix of basic physics, optics, nanofabrication, atomic physics, and engineering, combined with integration with electronics and data systems. Very multi-disciplinary.
- Defining parameters is important not everything is achievable all the time.
- Once a device is developed, users immediately come up with a way to use them to measure something new and ask for even better devices.